



[> home](#) [> about](#) [> feedback](#) [> login](#)

US Patent & Trademark Office



Try the *new* Portal design

Give us your opinion after using it.

Search Results

Nothing Found

Your search for the *Phrase* (**density <AND> volume <AND> "normalized device space"**) did not return any results.

To search for *terms* separate them with **AND** or **OR**.

Click on the suggested options:

(density AND <AND> AND volume AND <AND> AND "normalized AND device AND space")

(density OR OR volume OR OR "normalized OR device OR space")

To search for names try using only the last or first name.

You may revise it and try your search again below or click advanced search for more options.

(density <AND> volume
<AND> "normalized device
space")



[\[Advanced Search\]](#) [\[Search Help/Tips\]](#)



Complete Search Help and Tips

The following characters have specialized meaning:

Special Characters	Description
, () [These characters end a text token.
= > < !	These characters end a text token because they signify the start of a field operator. (! is special: != ends a token.)
` @ \Q < { [!	These characters signify the start of a delimited token. These are terminated by the end character associated with the start character.

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.5Welcome
United States Patent and Trademark Office[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)» [Se](#)

Welcome to IEEE Xplore®

Your search matched **[0]** of **[987604]** documents.

- ☐ [Home](#)
- ☐ [What Can I Access?](#)
- ☐ [Log-out](#)

Tables of Contents

- ☐ [Journals & Magazines](#)
- ☐ [Conference Proceedings](#)
- ☐ [Standards](#)

Search

- ☐ [By Author](#)
- ☐ [Basic](#)
- ☐ [Advanced](#)

Member Services

- ☐ [Join IEEE](#)
- ☐ [Establish IEEE Web Account](#)
- ☐ [Access the IEEE Member Digital Library](#)

[Print Format](#)

You may refine your search by editing the current search expression or entering a new one the text box. Then click search Again.

OR

Use your browser's back button to return to your original search page.

Results:

No documents matched your query.

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved